



TELECOM
ParisTech



Institut
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Mixed PUF-TRNG using Body Biasing in FD-SOI

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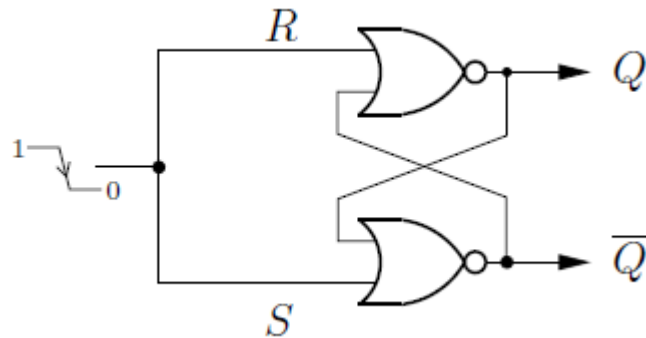
A decorative horizontal bar at the bottom of the slide, consisting of three colored segments: red, black, and brown.



Outline

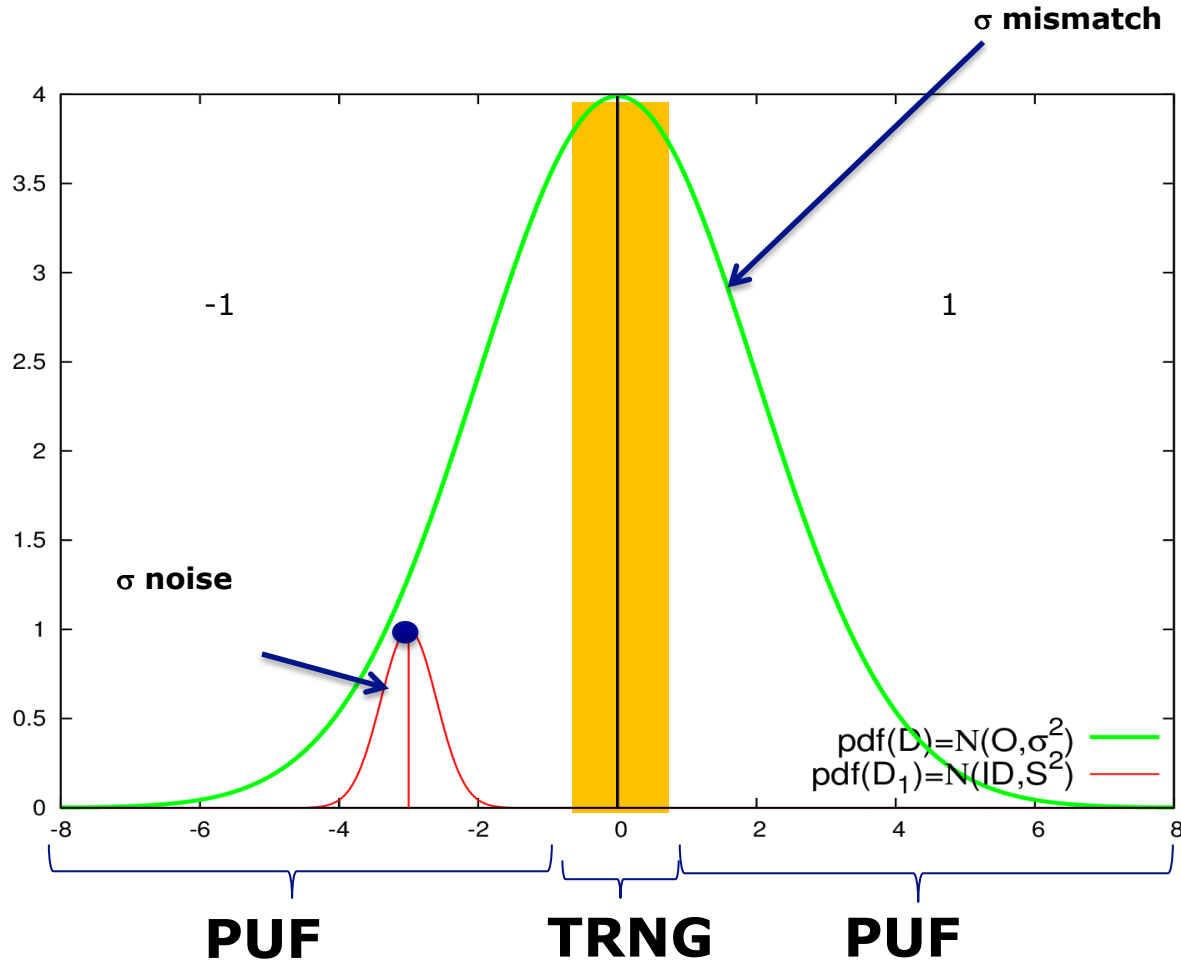
- Principle
- Analysis
- Conclusions

SR-latch as PUF -TRNG

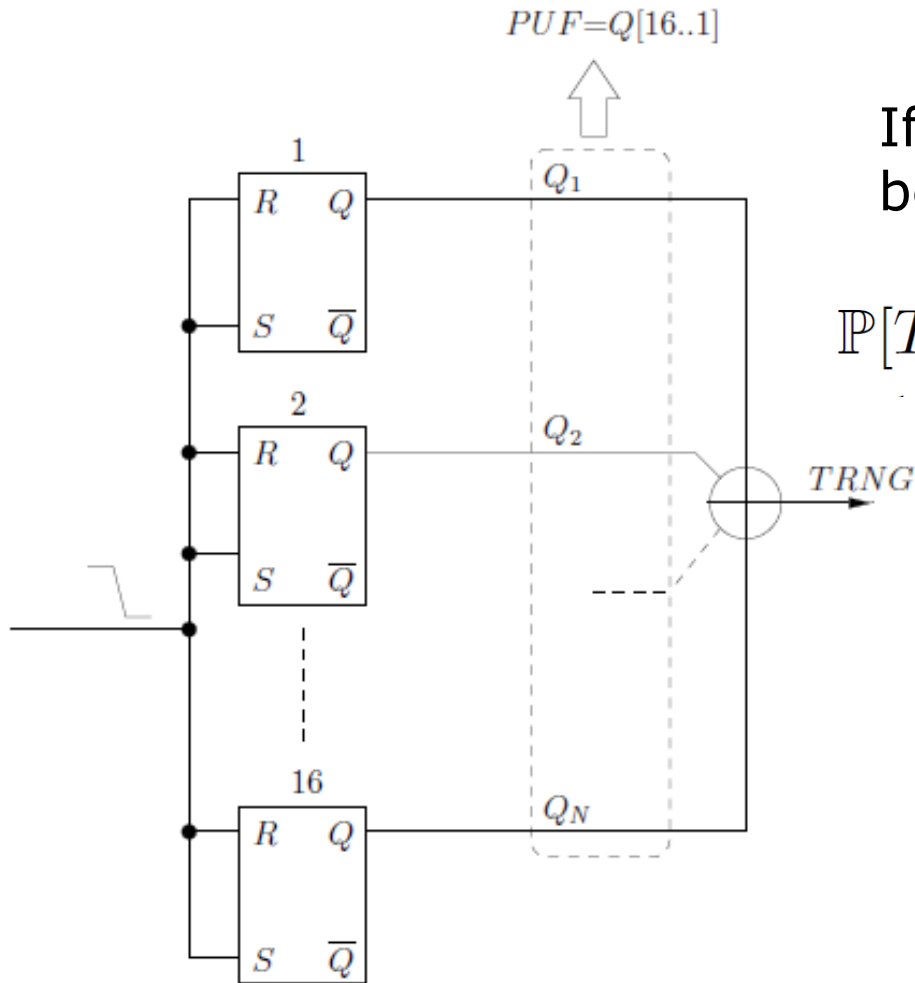


Small imbalance \Rightarrow metastability \Rightarrow **TRNG**
Big imbalance \Rightarrow stability \Rightarrow **PUF**

PUF-TRNG according to T-su distribution



SR-latch as PUF -TRNG



If noise is independent between latches:

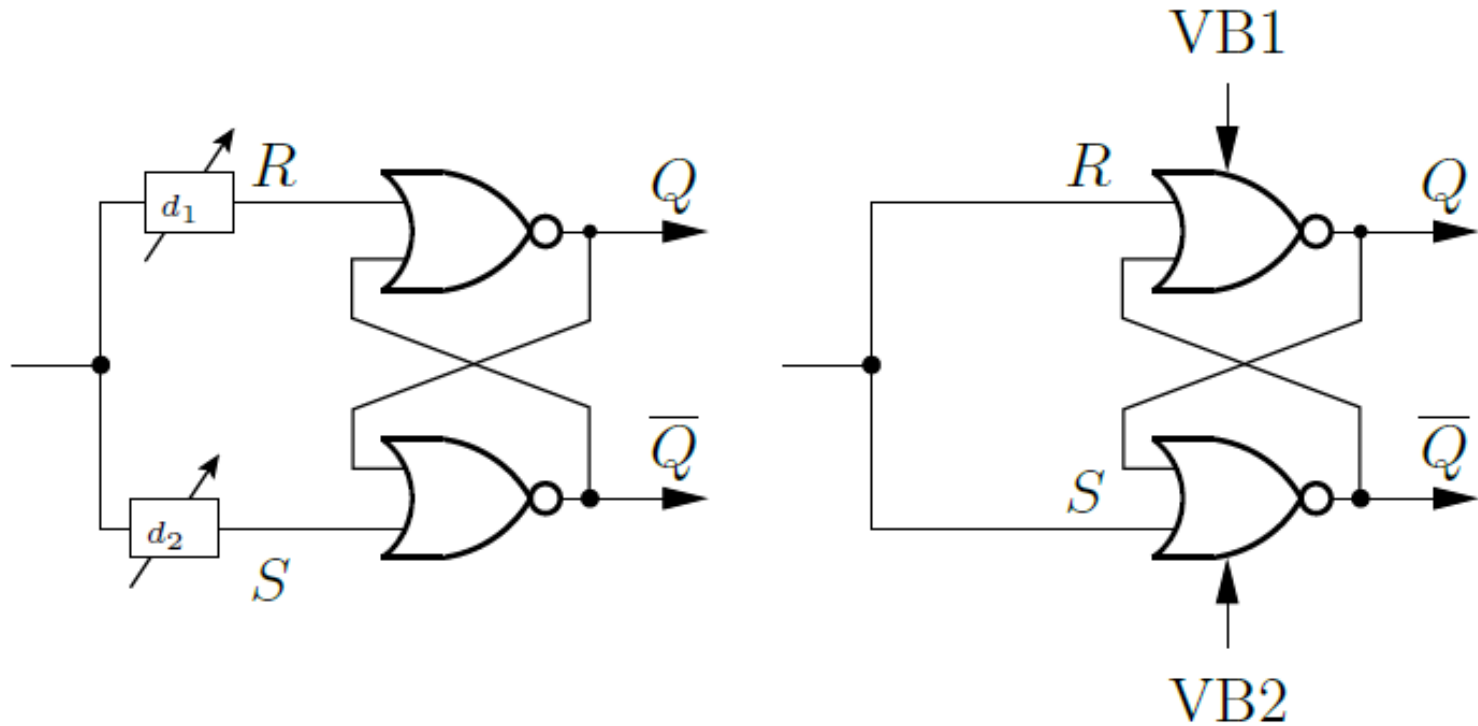
$$\mathbb{P}[TRNG = 0] = \frac{1 + (2p_i - 1)^N}{2}$$

$$\mathbb{P}[Q_i == 1] = p_i.$$

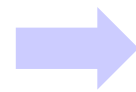
Entropy = 0.997 \rightarrow N = 12

AIS31

SR-latch T_{su} adjustment in FD-SOI

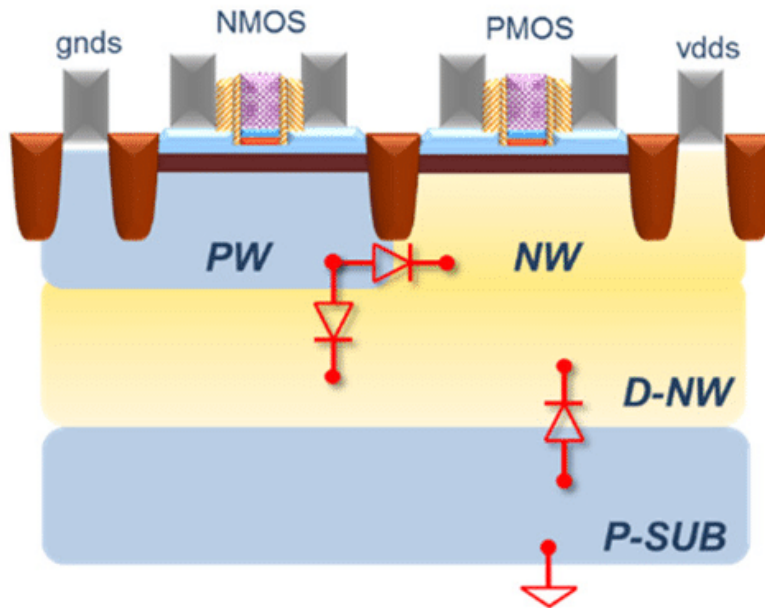


Delay adjustment
Not so easy to design in ASIC



FD-SOI Body biasing

FD-SOI Body bias



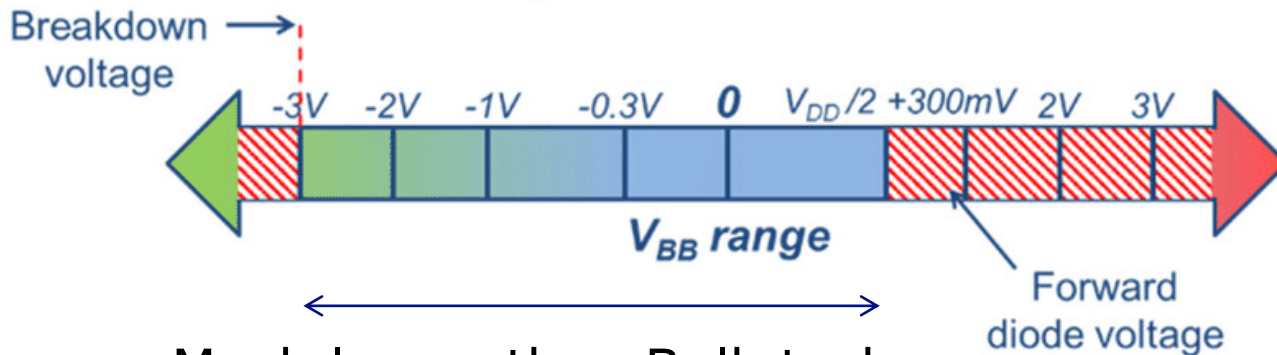
Well voltages

$$V_{DDs} = V_{DD} - V_{BB}$$

$$GNDs = V_{BB}$$

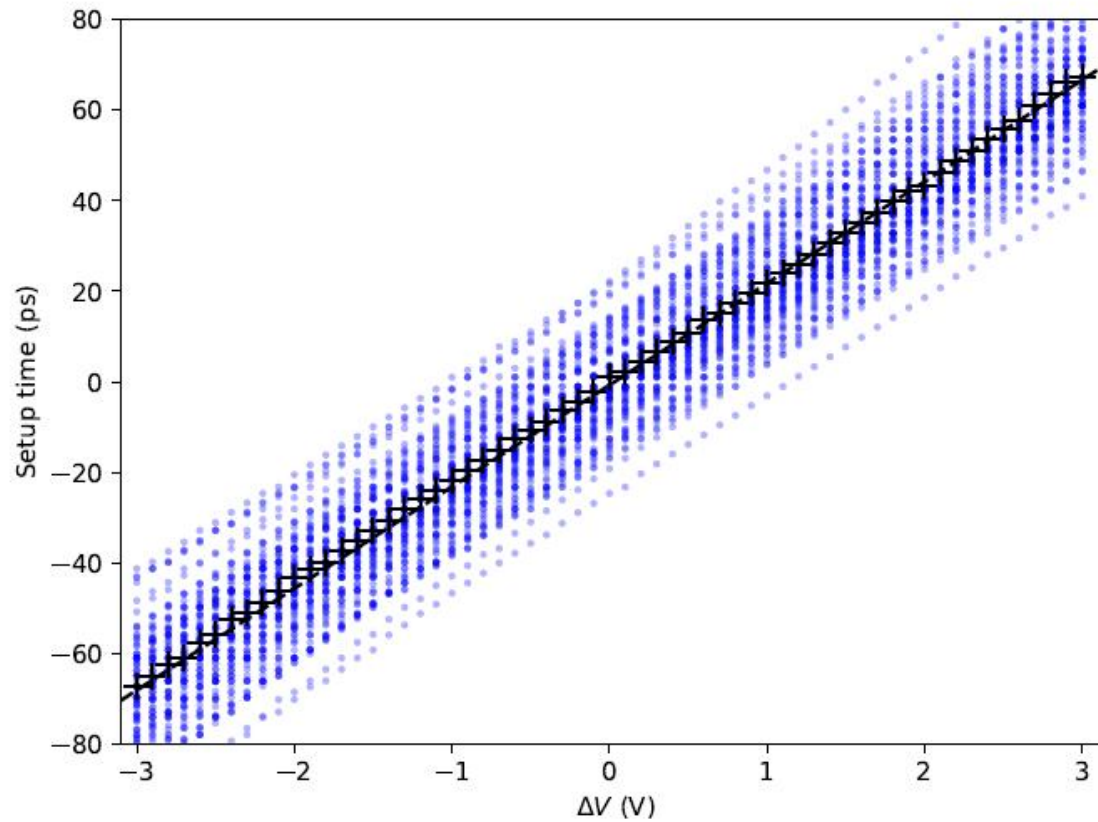
Back-Bias Range

$$-3V < V_{BB} < \frac{V_{DD}}{2} + 300mV$$



Much larger than Bulk techno

Set-up time vs Body Bias



$$\Delta V = VB1 - VB2$$



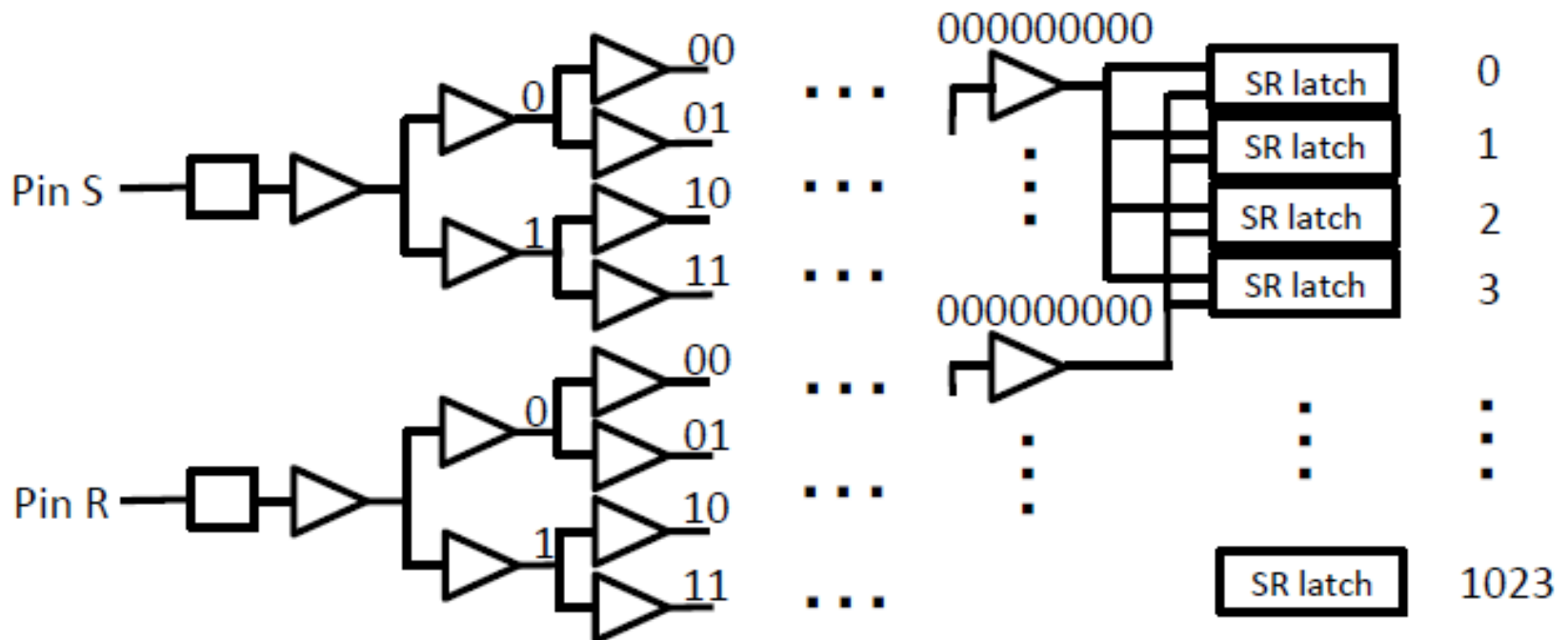
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Test chip architecture

1024 latches driven by a buffer tree

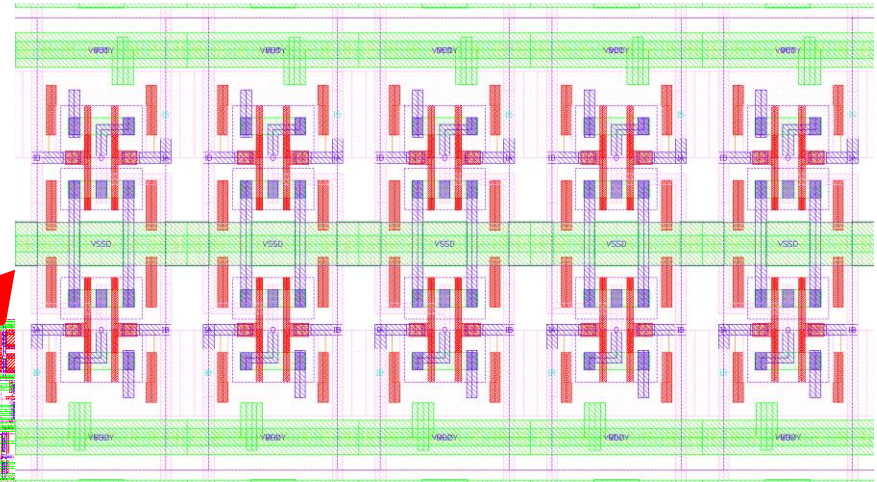
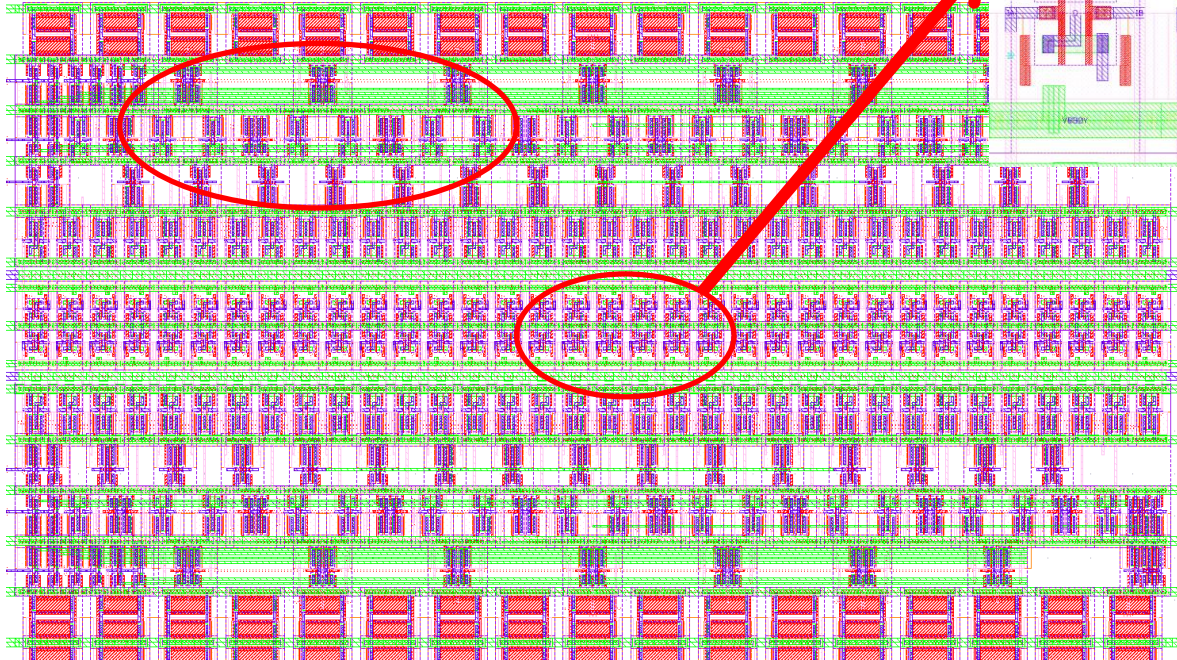
Address:



Techno = UTBB FD-SOI 28nm

Layout

buffers

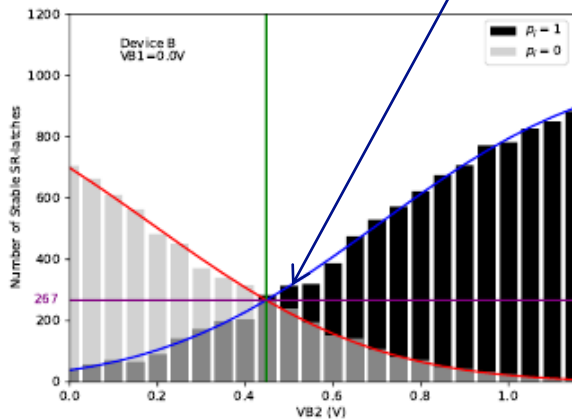


latches

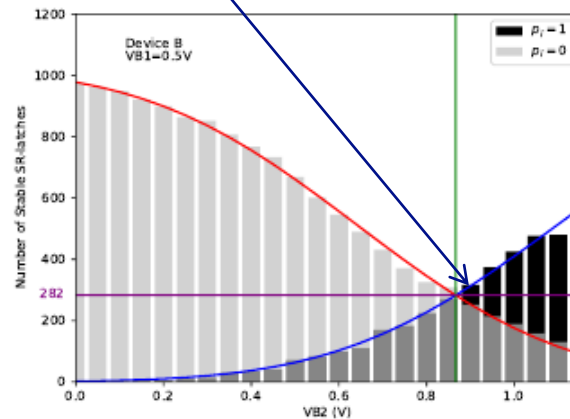
Adjustment by VB1-VB2 for PUF

PUF: number of stable latches (after 1000 tries)

Optimal point (max entropy)

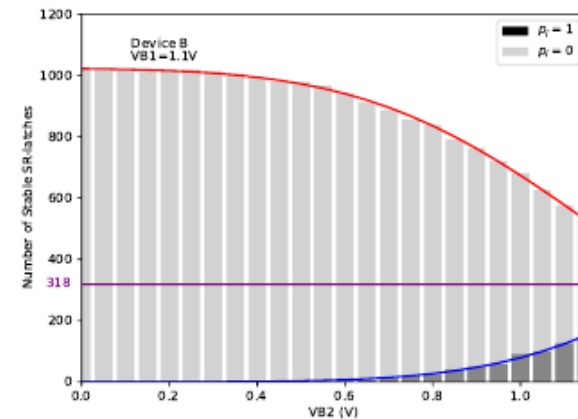


VB1 = 0V



(b) Device B

VB1 = 0.5V

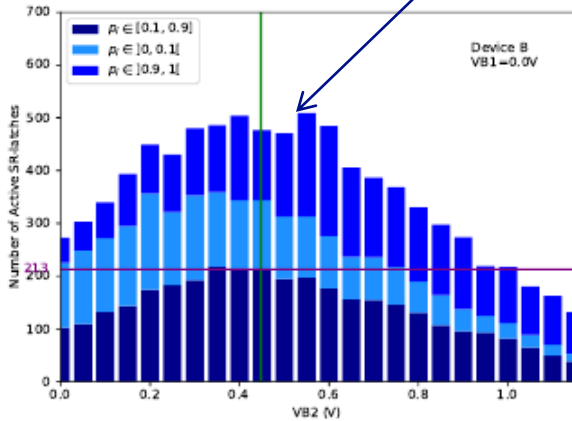


VB1 = 1.1V

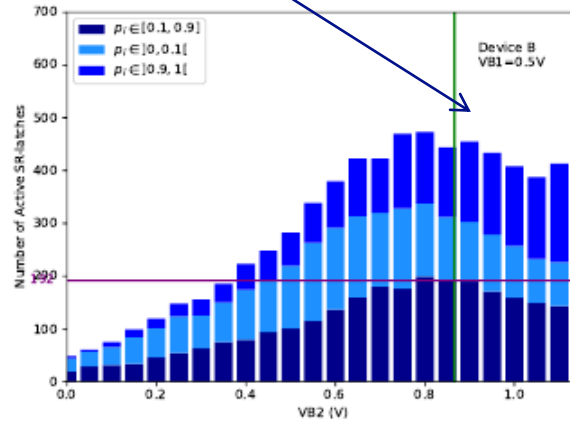
Adjustment by VB1-VB2 for TRNG

TRNG: number of unstable latches

Optimal point

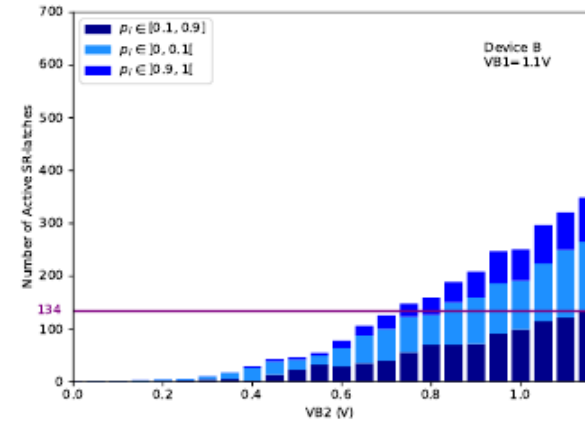


VB1 = 0V



(b) Device B

VB1 = 0.5V

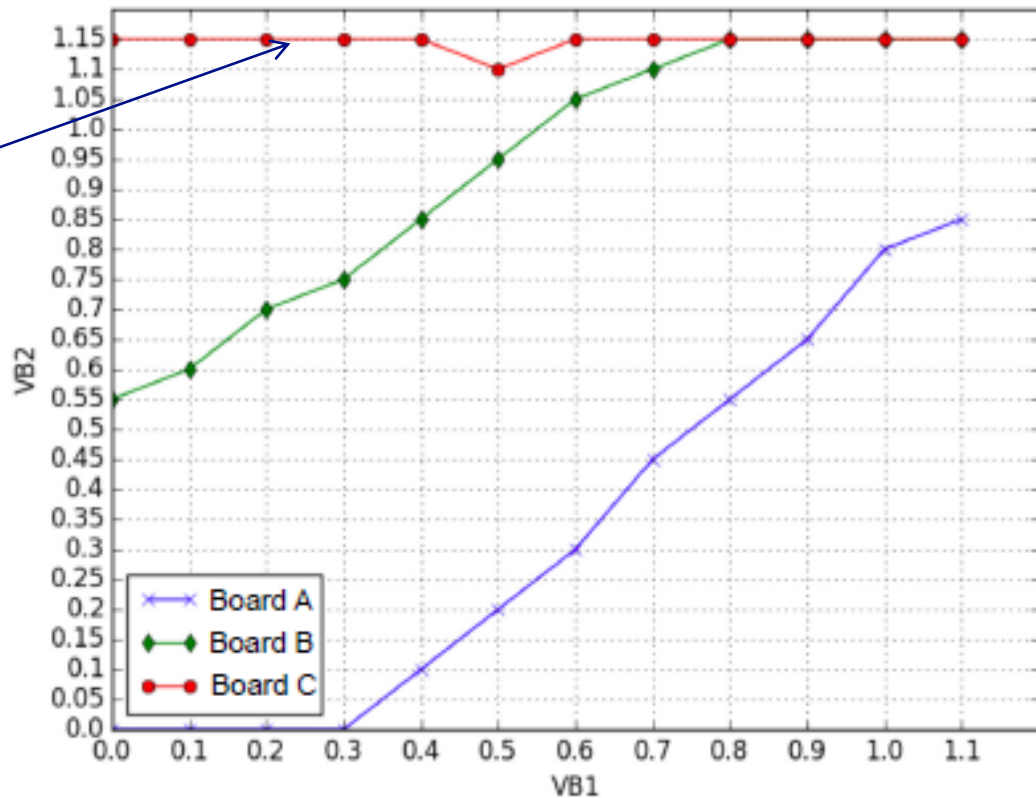


VB1 = 1.1V

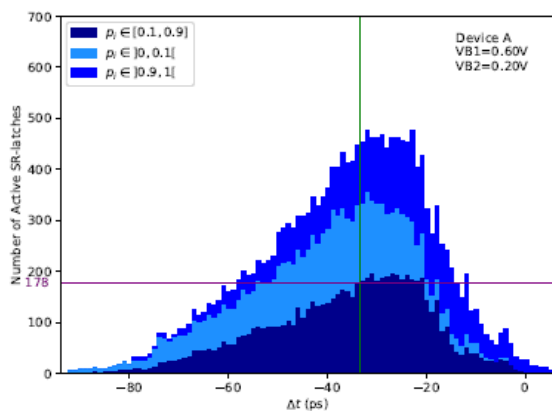
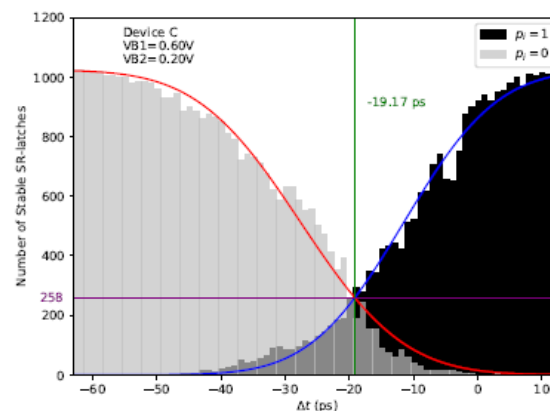
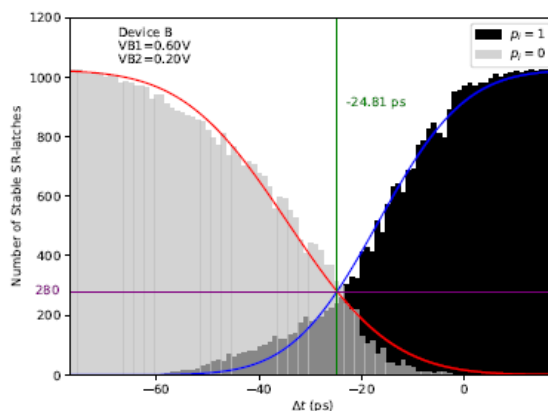
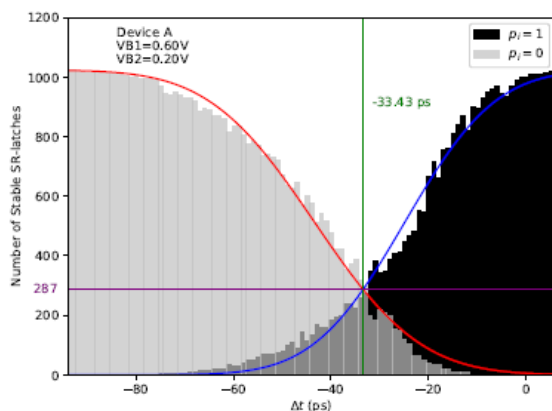
Optimal point: the same for PUF and TRNG !

VB1-VB2 at the optimal point is specific to a device

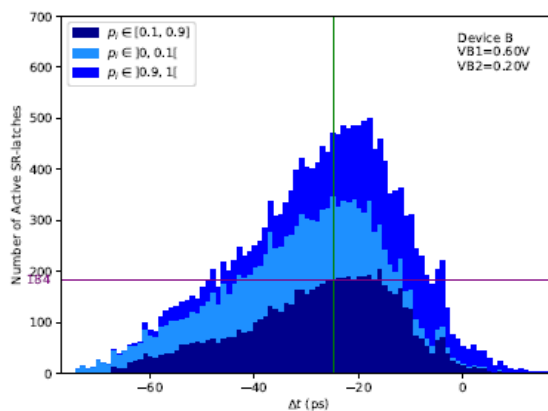
Device C not significant as the VB range is limited due to a bug in the test chip



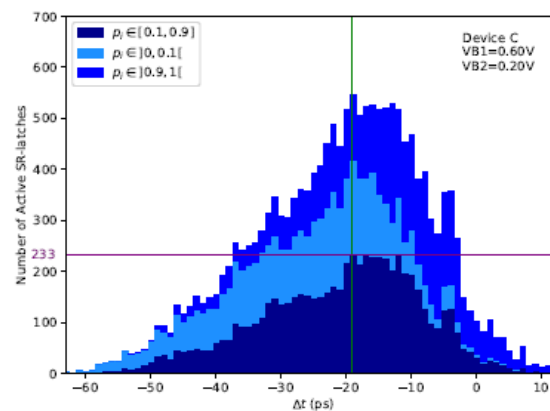
Analysis with the timing generator



(a) device A



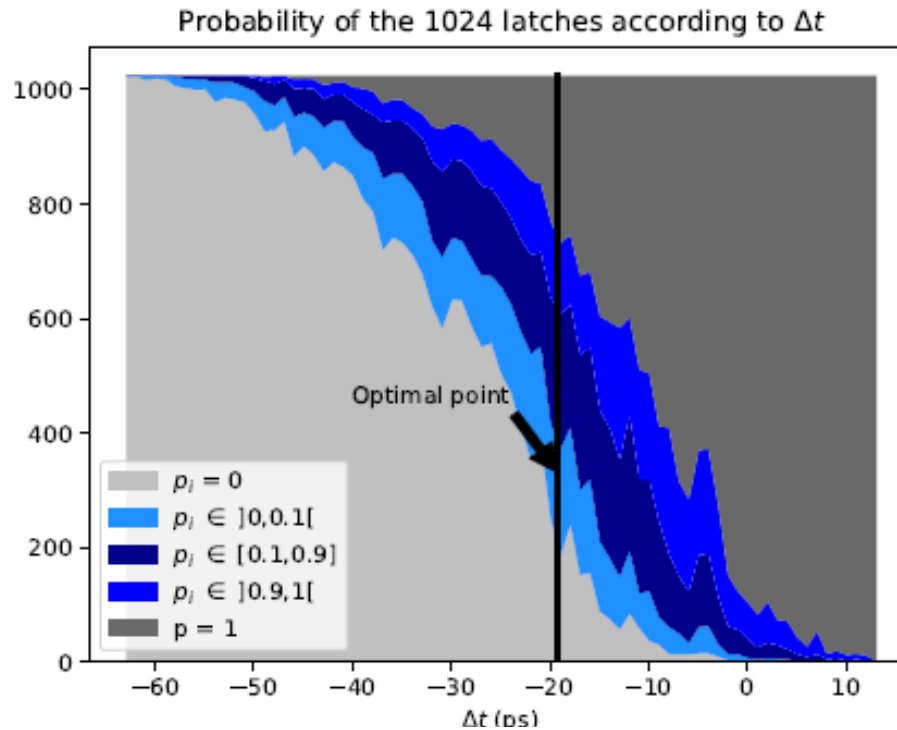
(b) device B



(c) device C

The optimal point is the same for the PUF and TRNG, but different from a device to another

Number of latches in PUF or TRNG at Optimal point

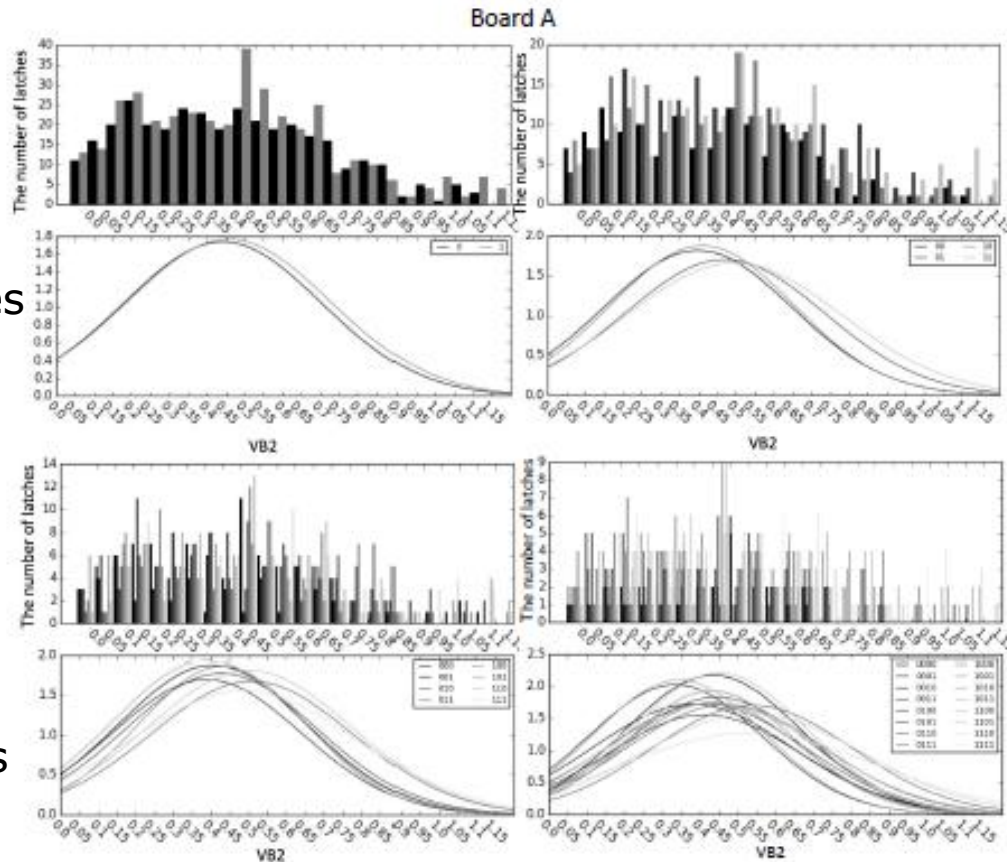


Device	Optimal point	stable latches at 0 or 1	unstable latches with $p_i \in [0.1, 0.9]$
A	-33.43ps	287	178
B	-24.81ps	280	184
C	-19.17ps	258	233

Table I: Number of latches at the optimal point.

Imbalance due to P/R

Number of latches with $p_i=0.5$



2 main branches

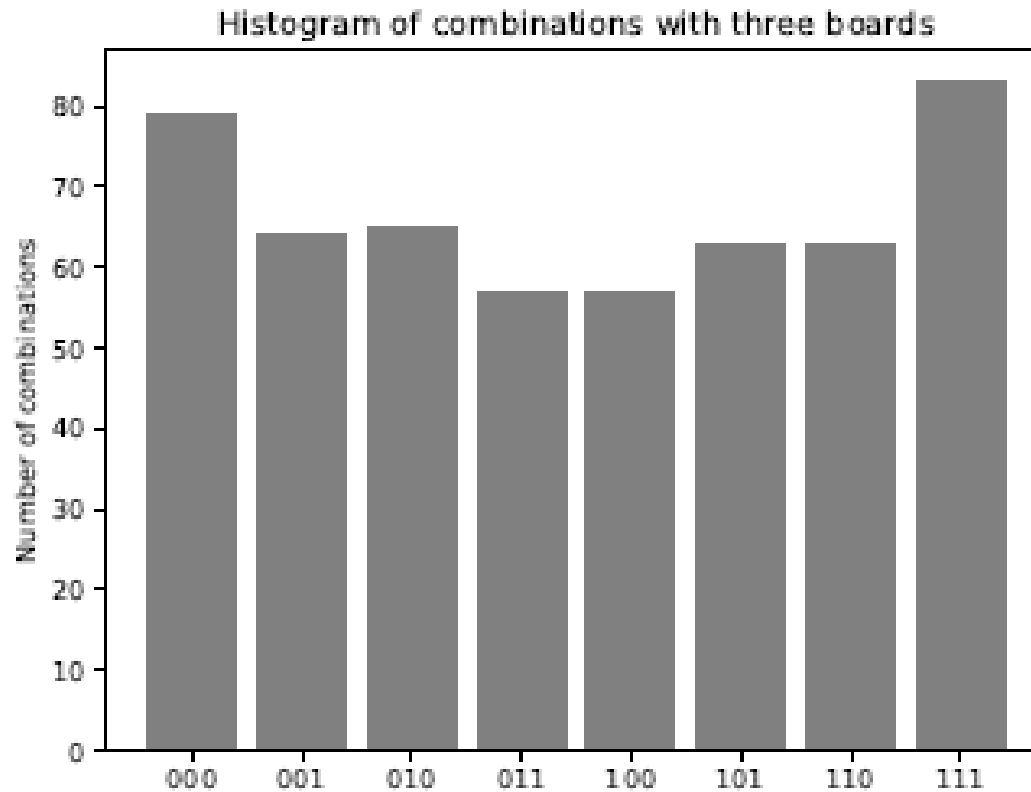
4 sub-branches

8 sub-branches

16 sub-branches

Entropy

Combinations for stable latches between 3 devices



$H=2.98$ bits

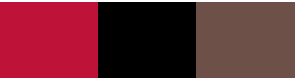


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Conclusions

- ❑ **Simple structure to get PUF-TRNG**
 - High speed TRNG
 - Reliable PUF as the reliability of each latch can be known
- ❑ **Every device needs to be adjusted to the optimal point**
 - The optimal point is when as many '0' as '1'
- ❑ **FD-SOI technology allows to obtain the optimal point by body biasing**
- ❑ **The buffer tree and the number of latches could be largely reduced**



THANK YOU FOR YOUR ATTENTION !